

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			
INFORMATION DISCLOSURE STATEMENT		Docket Number: 10191/3525	
Application Number To Be Assigned	Filing Date Herewith	Examiner	Art Unit
Invention Title <b>INTERFEROMETRIC MEASURING DEVICE</b>		Inventor(s) Jochen STRAEHLE	

Address to:  
Mail Stop Patent Application  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, 22313-1450

- I. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant hereby bring the following references to the attention of the Examiner. The references are listed on the attached modified PTO Form No. 1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
- II. A copy of each patent, publication or other information listed on the modified PTO form 1449 is enclosed, except as otherwise indicated on the modified PTO form 1449.

Dated:

1/21/04

By:

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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449</b>	<b>ATTY. DOCKET NO.</b> 10191/3525	<b>SERIAL NO.</b> Not yet assigned
	<b>APPLICANT(s)</b> Jochen STRAEHLE	
	<b>FILING DATE</b> Herewith	<b>GROUP</b> Not yet assigned

**U. S. PATENT DOCUMENTS**

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE

**FOREIGN PATENT DOCUMENTS**

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
						YES	NO
	100 47 495	Oct. 25, 2001	DE			X*	
	101 31 780	March 7, 2002	DE			X*	
	100 39 239	March 7, 2002	DE			X*	
	101 31 779	Feb. 28, 2002	DE			X*	

**OTHER DOCUMENTS**

EXAMINER INITIAL		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
		P. Ney, A. Maillard and M.D. Fontana, J. Opt. Soc. Am. B/Vol. 7, No. 7/July 2000, pages 1158-1165.*

\*Described in specification.

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	